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# **RF Exposure Evaluation Report**

**Report No.:** CQASZ20241002192E-02

Applicant: Chengdu Xiaochen Technology Co., Ltd

Address of Applicant: 3rd Floor, Building B15, Ganzhizhongguo Chengdu Center, No. 777 Huafu

Avenue Shuangliu County, Chengdu City, Sichuan province, China

**Equipment Under Test (EUT):** 

**EUT Name:** VERTU AI FORTUNE RING

**Test Model No.:** VAIR11002-9, VAIR11002-10

Model No.: VAIR11002-10

Brand Name: ivertu

 FCC ID:
 2BGHD-VAIR11-10

 Standards:
 47 CFR Part 1.1307

47 CFR Part 2.1093

447498 D04 Interim General RF Exposure Guidance v01

**Date of Receipt:** 2024-10-15

**Date of Test:** 2024-10-15 to 2024-10-23

**Date of Issue:** 2024-11-26

Test Result: PASS\*

\*In the configuration tested, the EUT complied with the standards specified above

Tested By:

(Lewis Zhou)

Reviewed By:

(Timo Lei)

Approved By:

(Alex Wang)



The test report is effective only with both signature and specialized stamp, The result(s) shown in this report refer only to the sample(s) tested. Without written approval of CQA, this report can't be reproduced except in full.



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# 1 Version

# **Revision History Of Report**

Report No.	Version	Description	Issue Date	
CQASZ20241002192E-02	Rev.01	Initial report	2024-11-26	



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# **3** General Information

### 3.1 Client Information

Applicant:	Chengdu Xiaochen Technology Co., Ltd			
Address of Applicant:	3rd Floor, Building B15, Ganzhizhongguo Chengdu Center, No. 777 Huafu Avenue Shuangliu County ,Chengdu City, Sichuan province ,China			
Manufacturer:	Chengdu Xiaochen Technology Co., Ltd			
Address of Manufacturer:	3rd Floor, Building B15, Ganzhizhongguo Chengdu Center, No. 777 Huafu Avenue Shuangliu County ,Chengdu City, Sichuan province ,China			
Factory:	Chengdu Xiaochen Technology Co., Ltd			
Address of Factory:	3rd Floor, Building B15, Ganzhizhongguo Chengdu Center, No. 777 Huafu Avenue Shuangliu County ,Chengdu City, Sichuan province ,China			

# 3.2 General Description of EUT

Product Name:	VERTU AI FORTUNE RING
Model No.:	VAIR11002-9, VAIR11002-10
Test Model No	VAIR11002-10
Trade Mark:	ivertu
EUT Supports Radios application:	Bluetooth mode 2402-2480MHz
Software Version:	2301A V0.4.8.6
Hardware Version:	2301A V3
Sample Type:	☐ Mobile ☐ Portable
EUT Power Supply:	Li-ion battery: DC 3.7V 18.5mAh, Charge by DC 5V for Charge box

# 3.3 General Description of BLE

Operation Frequency:	2402MHz~2480MHz
Bluetooth Version:	V5.0
Modulation Technique:	Non Frequency Hopping Spread Spectrum(NFHSS)
Modulation Type:	GFSK
Number of Channel:	BLE:40
Transfer Rate:	BLE:1Mbps
Test Software of EUT:	nrfgostudio
Antenna Type:	Chip antenna
Antenna Gain:	0.5dBi



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### 4 SAR Evaluation

### 4.1 RF Exposure Compliance Requirement

#### 4.1.1 Standard Requirement

447498 D04 Interim General RF Exposure Guidance v01

3.2. SAR Test Reduction Guidance

SAR test reduction procedures [Glossary] allow using a particular set of test data as representative of other, similar, test conditions. This may be applied for data within different test positions (e.g. body, head, extremity), wireless modes (e.g. Wi-Fi, cellular), and frequency bands. This test reduction process provides for the use of test data for one specific channel, while referencing to those data for demonstrating compliance in other required channels for each test position of an exposure condition, within the operating mode of a frequency band. This is limited specifically to when the reported 1-g or 10-g SAR for the mid-band or highest output power channel meets any of the following conditions.

#### **4.1.2 Limits**

SAR-based thresholds are derived based on frequency, power, and separation distance of the RF source. The formula defines the thresholds in general for either available maximum time averaged power or maximum time-averaged ERP, whichever is greater.

If the ERP of a device is not easily determined, such as for a portable device with a small form factor, the applicant may use the available maximum time-averaged power exclusively if the device antenna or radiating structure does not exceed an electrical length of  $\lambda$  /4.

As for devices with antennas of length greater than  $\lambda$  /4 where the gain is not well defined, but always less than that of a half-wave dipole (length  $\lambda$  /2), the available maximum time-averaged power generated by the device may be used in place of the maximum time-averaged ERP, where that value is not known.

The separation distance is the smallest distance from any part of the antenna or radiating structure for all persons, during operation at the applicable ERP. In the case of mobile or portable devices, the separation distance is from the outer housing of the device where it is closest to the antenna.

The SAR-based exemption formula of § 1.1307(b)(3)(i)(B), repeated here as Formula (B.2), applies for single fixed, mobile, and portable RF sources with available maximum time-averaged power or effective radiated power (ERP), whichever is greater, of less than or equal to the threshold Pth (mW).

This method shall only be used at separation distances from 0.5 cm to 40 cm and at frequencies from 0.3 GHz to 6 GHz (inclusive). Pth is given by Formula (B.2).



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$$P_{\text{th}} (\text{mW}) = \begin{cases} ERP_{20 \text{ cm}} (d/20 \text{ cm})^x & d \le 20 \text{ cm} \\ ERP_{20 \text{ cm}} & 20 \text{ cm} < d \le 40 \text{ cm} \end{cases}$$
(B. 2)

where

$$x = -\log_{10}\left(\frac{60}{ERP_{20}\operatorname{cm}\sqrt{f}}\right)$$

and f is in GHz, d is the separation distance (cm), and  $ERP_{20cm}$  is per Formula (B.1). The example values shown in Table B.2 are for illustration only.

Table B.2—Example Power Thresholds (mW)

	Distance (mm)										
		5	10	15	20	25	30	35	40	45	50
Hz)	300	39	65	88	110	129	148	166	184	201	217
(MH	450	22	44	67	89	112	135	158	180	203	226
	835	9	25	44	66	90	116	145	175	207	240
Frequency	1900	3	12	26	44	66	92	122	157	195	236
nba	2450	3	10	22	38	59	83	111	143	179	219
Fre	3600	2	8	18	32	49	71	96	125	158	195
	5800	1	6	14	25	40	58	80	106	136	169



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# 4.1.3 EUT RF Exposure

#### **Measurement Data**

Channel	Conducted Peak Output Power (dBm)	EIRP (dBm)	Maximum tune-up Power (mW)	Exclusion threshold (mW)
Lowest (2402MHz)	-3.48	-2.98	0.504	
Middle (2440MHz)	-3.52	-3.02	0.499	3.0
Highest (2480MHz)	-1.72	-1.22	0.755	

Remark: The Max Conducted Peak Output Power data refer to report Report No.: CQASZ20241002192E-01.

\*\*\* END OF REPORT \*\*\*